# **Supporting Information**

# Steering Micromotors via Reprogrammable

# **Optoelectronic Paths**

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## 1. SEM of Janus SiO<sub>2</sub>-Pt Micromotor



Figure S1. Scanning electron microscope image of a SiO<sub>2</sub>-Pt Janus microsphere.

#### 2. Numerical simulations

To simulate the distributions of electric fields, a 3D finite element model was built in COMSOL Multiphysics (version 5.4) using Electric Current and Creeping Flow module. The model length (X-axis), width (Y-axis) and height (Z-axis) were set to be 500  $\mu$ m, 500  $\mu$ m, and 200  $\mu$ m, respectively. The model included a 0.2  $\mu$ m ITO and 1- $\mu$ m-thick a-Si:H layer at the bottom and a 198.8- $\mu$ m-thick liquid chamber.

The illuminated domain is a thin slab of  $100 \times 100 \times 1$  µm embedded at the bottom, and its electrical conductivity is set to be two orders of magnitude higher than the rest of the surface that is assumed to remain in darkness. The top surface of the entire solvable domain is grounded while the bottom surface (ITO layer) is set to 10V. Other surfaces are set to be insulating. See Fig. 3d for the configuration. Parameters were chosen following ref. 1.

In the Electric Current module, the boundary conditions were set to perfect electrical insulation at the sides. Top surface is grounded while the bottom surface is set to 10V to simulate the applied AC signal (frequency set to 100 kHz). The electric potential and electric field were calculated by solving the continuity equations:

$$\nabla \cdot \boldsymbol{J} = Q_{j,v} \tag{Eqn. S1}$$

$$\boldsymbol{J} = \sigma \boldsymbol{E} + j\omega \boldsymbol{D} + \boldsymbol{J}_e \qquad (Eqn. \ S2)$$

$$\boldsymbol{E} = -\nabla V \qquad (Eqn. \ S3)$$

where J is the current density,  $Q_{j,v}$  is the volumetric source of current,  $\sigma$  is the electrical conductivity, E is the electric field,  $\omega$  is the angular frequency, D is the electric displacement,  $J_e$  is the externally generated current density, and V is the electrical potential.

Parameters used for this 3D model are listed in Table S1.

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Parameter	Description	Value
$\sigma_{\rm m}$	Conductivity of medium	5×10 <sup>-5</sup> S/m
ε <sub>m</sub>	Electrical permittivity of medium	$80\varepsilon_0$
$\sigma_{silicon-light}$	Conductivity of amorphous silicon in the light	1×10 <sup>-4</sup> S/m
σsilicon-dark	Conductivity of amorphous silicon in the dark	1×10 <sup>-6</sup> S/m
Esilicon	Electrical permittivity of silicon	$11.7\epsilon_{0}$

 Table S1 COMSOL parameters for the optoelectronic system simulation

$\sigma_{ITO}$	Conductivity of ITO	$5 \times 10^5 \text{ S/m}$
8ITO	Electrical permittivity of ITO	4

Figure S2 below shows the simulation results of electrical potential and electric fields.



**Figure S2.** Additional results of the distributions of electrical potential and electric fields on the x-z cut plane. a): electrical potential. b): z (vertical) component of the electric field. c): x (horizontal or tangential) component of the electric field. Models are configurated according to Fig. S2, and the same as Fig. 3d and e in the main text.

#### 3. Calculation of Re (K)

Re (K) is the real part of the Clausius–Mossotti factor. For calculation Re(K) of pure SiO<sub>2</sub>, the expression is shown as follow:

$$K = \frac{\varepsilon_{\rm p}^* - \varepsilon_{\rm m}^*}{\varepsilon_{\rm p}^* + 2\varepsilon_{\rm m}^*}$$
(Eqn. S4)

$$\varepsilon_{\rm p}^* = \varepsilon_{\rm p} - i \frac{\sigma_{\rm p}}{\omega} \tag{Eqn. S5}$$

$$\varepsilon_{\rm m}^* = \varepsilon_{\rm m} - i \frac{\sigma_{\rm m}}{\omega}$$
 (Eqn. S6)

where  $\varepsilon_m$  and  $\varepsilon_p$  are the permittivity of the medium and the particle, and  $\sigma_m$  and  $\sigma_p$  are electrical conductivity of medium and particle.  $\omega$  is the driving frequency of the electric field.

The  $\sigma_m$  of a 1:1 electrolyte of valence of z is:

$$\sigma_{\rm m} = \sigma_{\rm m}^+ + \sigma_{\rm m}^- = \frac{z^2 e^2 N_A c_0}{k_{\rm B} T} (D^+ + D^-)$$
 (Eqn. S7)

where + and - correspond to the cation and anion, respectively, and *D* is the ion diffusivity.  $c_0$  is the ion concentration in the bulk, and N<sub>A</sub> is the Avogadro number.

As preparing core-shell Pt-coated particles can be challenging, we have opted to use core-shell Ag-coated  $SiO_2$  particles as an example to calculate the core-shell metal-coated  $SiO_2$  particles. The expression for this calculation is shown below:

$$K = \frac{\varepsilon_{\text{core-shell}}^* - \varepsilon_{\text{m}}^*}{\varepsilon_{\text{core-shell}}^* + 2\varepsilon_{\text{m}}^*}$$
(Eqn. S8)

$$\varepsilon_{core-shell}^* = \varepsilon_{Ag}^* \left[ \gamma^3 + 2 \left( \frac{\varepsilon_{SiO_2}^* - \varepsilon_{Ag}^*}{\varepsilon_{SiO_2}^* + 2\varepsilon_{Ag}^*} \right) \right] / \left[ \gamma^3 - \left( \frac{\varepsilon_{SiO_2}^* - \varepsilon_{Ag}^*}{\varepsilon_{SiO_2}^* + 2\varepsilon_{Ag}^*} \right) \right]$$
(Eqn. S9)

$$\gamma = \left(\frac{R}{r}\right)^3 \tag{Eqn. S10}$$

$$\varepsilon^*_{SiO_2} = \varepsilon^*_p \tag{Eqn. S11}$$

$$\varepsilon_{Ag}^* = \varepsilon_{Ag} - i \frac{\sigma_{Ag}}{\omega}$$
 (Eqn. S12)

where R and r are the outside and inner radius of Ag-coated SiO<sub>2</sub>,  $\epsilon_{Ag}$  is the permittivity of Ag,  $\sigma_{Ag}$  is the electric conductivity of Ag.

The values used in calculating  $\operatorname{Re}(K)$  are listed in Table S2.

Parameter	Description	Value
Т	Temperature	293.15 K
$\zeta_{ m p}$	Particle zeta potential	-0.05 V
ε <sub>m</sub>	Electrical permittivity of water	$78.5\varepsilon_0$
ε <sub>p</sub>	Electrical permittivity of SiO <sub>2</sub>	<b>3.9</b> ε <sub>0</sub>
ε <sub>Ag</sub>	Electrical permittivity of Ag	1×10 <sup>9</sup>
$D_+$	Diffusivity of Na <sup>+</sup>	$1.33 \times 10^{-9} \text{ m}^2 \cdot \text{s}^{-1}$
D.	Diffusivity of Cl <sup>-</sup>	$2.03 \times 10^{-9} \text{ m}^2 \cdot \text{s}^{-1}$
η	Dynamic viscosity of water at 293.15 K	1.0016×10 <sup>-3</sup> Pa·s <sup>-1</sup>
$\sigma_p$	Conductivity of SiO <sub>2</sub>	$1 \times 10^{-10} \text{ S} \cdot \text{m}^{-1}$
$\sigma_{Ag}$	Conductivity of Ag	$6.3 \times 10^6  \mathrm{S} \cdot \mathrm{m}^{-1}$

**Table S2** Parameters for calculating Re(K)

r	Radius of SiO <sub>2</sub>	2.5×10 <sup>-6</sup> m
R	Radius of Ag-coated SiO <sub>2</sub>	2.51×10 <sup>-6</sup> m
<b>C</b> 0	Ion concentration of bulk solution	$1 \times 10^{-4} \text{ mol} \cdot \text{L}^{-1}$

Re(K) of Janus metal-SiO<sub>2</sub> microsphere can be calculated by averaging the Re(K) of pure SiO<sub>2</sub> microsphere and core-shell metal-coated SiO<sub>2</sub> microsphere.<sup>2</sup>

#### 4. Explanation of using 0.1 mM NaCl liquid medium in our experiment

It is found that the ICEP self-propulsion micromotor at 100 kHz is strong at the 0.1 mM NaCl liquid medium, making it easy to control the movement of the micromotor in the OET system.

For the metallo-dielectric Janus particle, the self-propulsion speed is dependent on the electric field frequency.<sup>3</sup> At low frequency, Janus particle move with dielectric side forward due to ICEP. At low frequencies, the Janus particle moves with the dielectric side forward due to ICEP. However, as the frequency increases, the speed of the Janus particle slows down because the ions are unable to follow the rapid changes of the electric field, thereby failing to establish a fully charged electrical double layer (EDL). When the frequency reaches a crossover frequency, the Janus particle reverses its direction of movement.

In the OET system, the ICEP micromotor moves slowly at low ionic concentrations, likely because the driving frequency is close to the crossover frequency. As the charging frequency of the EDL scales with the square root of the ionic concentration, the crossover frequency increases with higher ionic concentrations. Therefore, increasing the ionic concentration to 0.1 mM enables the driving frequency of OET to be within the range that induces the ICEP effect, resulting in strong self-propulsion of the Janus particle. However, further increases in ionic concentration can weaken the ICEP speed due to screening of the electric field at high conductivity.<sup>4</sup> Therefore, we select the 0.1 mM NaCl liquid medium to perform our experiment.

#### 4. Other supporting figures



**Figure S3.** Speeds of SiO<sub>2</sub>-Pt micromotors undergoing ICEP under different driving voltages in a typical sandwich electrode configuration (i.e., not an optoelectronic device)



Figure S4. Speeds of SiO<sub>2</sub>-Pt micromotors undergoing ICEP in an optoelectronic

device at different electric field conditions. (a, b): Motor speeds under constant illumination but varying voltages. (c, d): Motor speeds under constant voltages but varying light intensities.



**Figure S5.** Alignment of metallo-dielectric Janus microspheres in an electric field. Here, polystyrene-gold Janus microspheres of 5  $\mu$ m in diameter were suspended between two ITO electrodes separated by 200  $\mu$ m. Upon turning on an AC electric field, their Janus interfaces quickly aligned with the field lines so they appeared half-black and half-white under an optical microscope.



**Figure S6.** Both a  $SiO_2$  microsphere (a) and a  $SiO_2$  microsphere coated with an Ag shell (b) move to the light pattern's edge under an AC electric field of 100 kHz, exhibiting positive dielectrophoresis.



**Figure S7.** Two Janus SiO<sub>2</sub>-Pt micromotors move clockwise or counterclockwise, respectively, in the circular light pattern under an AC electric field of 100 kHz.

# 5. Supporting Videos

All videos play at real time unless otherwise noted.

Video S1: SiO<sub>2</sub>-Pt micromotors undergoing ICEP in and outside light patterns, corresponding to Figure 1c, d in the main text.

Video S2: SiO<sub>2</sub>-Pt micromotors accumulating at and moving along light patterns, corresponding to Figure 2b, c in the main text.

Video S3: SiO<sub>2</sub>-Pt micromotors steered by static light patterns, corresponding to Figure 4 in the main text.

Video S4: Spiral, helical and linear motion of a micromotor in dynamic light patterns, corresponding to Figure 5 in the main text.

Video S5: Collection and transport of five SiO<sub>2</sub>-Pt micromotors by a dynamic light pattern, corresponding to Figure 6 in the main text.

Video S6: Au-Pt micromotors confined by light patterns, corresponding to Figure 7.

## References

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